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Patent Number(s): JP2012123346-A
Title: Terahertz wave generation apparatus has terahertz wave filter provided with infrared-light scattering layer formed on surface of germanium wafer and removes infrared light component of laser beam
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Abstract: NOVELTY - The terahertz wave generation apparatus has a terahertz wave filter (S) provided with an infrared-light scattering layer (F) that is formed on the surface of the germanium wafer (E) and removes infrared light component of laser beam. A terahertz wave scattering layer provided on laser beam incident surface of terahertz wave filter, is formed with polyethylene powder of short wavelength and equivalent size to scatter terahertz wave (H).
USE - Terahertz wave generation apparatus.
ADVANTAGE - Obtains simple structure which produces favorable terahertz wave.
DESCRIPTION OF DRAWING(S) - The drawing shows a block diagram of the terahertz wave filter with infrared-light scattering layer. (Drawing includes non-English language text).
Nonlinear optical crystal (D)
Germanium wafer (E)
Infrared-light scattering layer (F)
Terahertz wave (H)
Terahertz wave filter (S)
Derwent Class Code(s): A89 (Photographic, laboratory equipment, optical); P81 (Optics); V07 (Fibre-optics and Light Control); X26 (Lighting - Discharge, incandescent and electric arc lamps)
Derwent Manual Code(s): A04-G02E; A12-L03D; V07-F02B; X26-Q01
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